

Co-Nanomet European Workshop

Thursday 19th Nov – Friday 20th Nov 2009, PTB, Braunschweig, DE

Technical Programme

	Thursday 19 th		Friday 20 th
09:45	Welcome Coffee & and Registration	08:45	Coffee
10:00	Introduction to Co-Nanomet: Dr. Theresa Burke, euspen	09:00	<p>Session 4: Engineered Nanoparticles Chair: Prof. Bernd Sachweh – BASF, DE Dr. Gert Roebben – JRC, BE</p> <p>Dr. Micheal Stintz, Technical University Dresden and CO-NANOMET <i>“Review of Nanometrology for Engineered Nanoparticles within Europe –Strengths & Opportunities”</i></p> <p>Prof. Bernd Sachweh – BASF, DE <i>“Industrial Production of Engineered Nanoparticles - Needs for European Nanometrology Strategy”</i></p> <p>Dr. Martin Hassellöv - University of Gothenburg, SE <i>“The Current State and Future Needs of Nanometrology for Environmental Risk Assessment of Engineered Nanoparticles”</i></p> <p>Dr. Stijn Put - Umicore, Belgium <i>“Nanometrology Needs for Industrial Nanopowder Producers”</i></p>
10:10	Welcome to PTB: Dr Harald Bosse, Head of Division, Precision Engineering	10:40	<p>Discussion Groups</p> <p>Breakout session for 5 topical areas:</p> <ul style="list-style-type: none"> • Engineered Nanoparticles • Nanobiotechnology • Thin Films and Structured Surfaces • Critical Dimensions and Scanning Probe Techniques • Modelling and Simulation <p>Each group will address: Current capabilities, emerging regulatory needs/developments and community issues relating to:</p> <ol style="list-style-type: none"> i) Measurement technologies ii) Instrumentation iii) Standardisation requirements iv) Traceability and equivalence v) Identification, development and implementation of tools for the assurance of measurement quality

10:25	Prof. Richard Leach, NPL, UK “European Strategy for Nanometrology”	12:40	Company Profile Session
10:40	Opening Talk: Dr. Alan Steele, Director Metrology, Institute for National, Measurement Standards National Research Council of Canada “Nanotechnology - International Standardisation and Metrological Requirements”	13:10	Lunch
11:00	Session 1: Thin Films and Structured Surfaces Chair: Prof. Laura Eleonoro Depero – University of Brescia, IT Dr. Gianbartolo Picotto, INRIM, IT Dr. Allan Pidduck - QinetiQ, UK & CO- NANOMET “Measurements of Thin Film Thickness & Other Parameters” Dr. Jean-Louis Stehle - Sopralab, FR “Thin film Analysis Using X-ray Reflectometry and Spectroscopic Ellipsometry” Dr. Ewald Niehus – IONTOF GmbH, DE Dr. Birgit Hagenhoff - TASCAN GmbH, DE “Chemical Analysis of Surfaces and Thin Films Using Ion Beam Techniques” Dr. Wolfgang Unger – BAM, DE “Achievements and Challenges in Metrology in Surface and Thin Film Analysis”	14:10	Session 5: Nanobiotechnology Chair: Dr. Debdulal Roy – NPL, UK & Dr. Richard Moore – Inst. of Nanotechnology, UK Assoc. Prof. Jukka Lausmaa – SP, SE and CO-NANOMET “European Nanometrology for Nanobiotechnology – Current Status and Future Challenges” Dr. Felix Kollmer - IONTOF GmbH, DE “SIMS Imaging at the Nanoscale - New Prospects with Cluster Ion Beams” Dr. Richard Moore – Institute of Nanotechnology, UK “Nanotechnology in Medical Applications” Dr. Hans Lingnert – Swedish Institutue of Food & Biotechnology, SE “Nanotechnology in Food Technology”
12:40	Lunch	15:50	Stakeholder Group Wash-up
13:40	Session 2: Critical Dimension and Scanning Probe Techniques Chair: Dr. Johann Foucher - CEA/LETI, FR & Dr. Allan Pidduck – QinetiQ, UK Dr.-Ing. Hans-Ulrich Danzebrink, PTB, DE “The Critical Dimensions and Scanning Probe Techniques within Europe - Current Capability and Future Directions” Dr. Johann Foucher - CEA-LETI, FR “The Critical Dimension Metrology Perspectives and Future Trends in the	16:10	Meeting Close

	<p>Semiconductor Industry”</p> <p>Dr. Peter de Wolf – Veeco, FR “An Overview of Industrial Applications for Scanning Probe Microscopy”</p> <p>Dr. Frank de Jong - FEI, NL “Focusing on (Scanning) Electron Microscopy Techniques for Metrology“</p>		
15:20	Coffee		
15:50	<p>Session 3: Modelling and Simulation Chair: Dr. Joergen Garnaes – Danish Fundamental Metrology, DK & Dr. Gerold Schroepfer – Coventor, FR</p> <p>Prof. Ana Proykova - University of Sofia, BG and CO-NANOMET “Modelling and Simulation for European Nanometrology – Current status, key developments and emerging needs”</p> <p>Dr. Gerold Schroepfer – Coventor, FR “Design Software and Metrology for MEMS Development”</p> <p>Dr. Anders Blom - QuantumWise, DK “Atomic Scale Modelling of the Electrical Properties of Nanostructures“</p>		
17:15	Company Profile Session		
17:45	Tour of PTB		
18:30	Transfer to Dinner Venue		